

**PRELIMINARY**

# CPV362M4U

## IGBT SIP MODULE

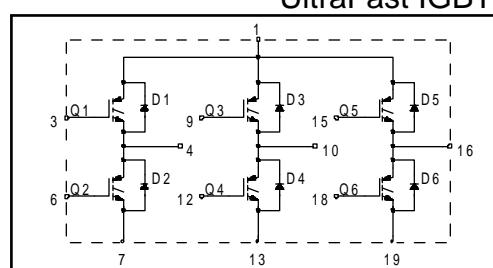
### Features

- Fully isolated printed circuit board mount package
- Switching-loss rating includes all "tail" losses
- HEXFRED™ soft ultrafast diodes
- Optimized for high operating frequency (over 5kHz)  
See Fig. 1 for Current vs. Frequency curve

### Product Summary

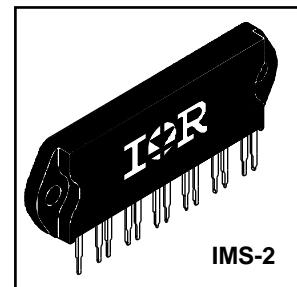
#### Output Current in a Typical 20 kHz Motor Drive

4.6 A<sub>RMS</sub> per phase (1.3 kW total) with T<sub>C</sub> = 90°C, T<sub>J</sub> = 125°C, Supply Voltage 360Vdc,  
Power Factor 0.8, Modulation Depth 115% (See Figure 1)



### Description

The IGBT technology is the key to International Rectifier's advanced line of IMS (Insulated Metal Substrate) Power Modules. These modules are more efficient than comparable bipolar transistor modules, while at the same time having the simpler gate-drive requirements of the familiar power MOSFET. This superior technology has now been coupled to a state of the art materials system that maximizes power throughput with low thermal resistance. This package is highly suited to motor drive applications and where space is at a premium.



### Absolute Maximum Ratings

	Parameter	Max.	Units
V <sub>CES</sub>	Collector-to-Emitter Voltage	600	V
I <sub>C</sub> @ T <sub>C</sub> = 25°C	Continuous Collector Current, each IGBT	7.2	A
I <sub>C</sub> @ T <sub>C</sub> = 100°C	Continuous Collector Current, each IGBT	3.9	
I <sub>CM</sub>	Pulsed Collector Current ①	22	
I <sub>LM</sub>	Clamped Inductive Load Current ②	22	
I <sub>F</sub> @ T <sub>C</sub> = 100°C	Diode Continuous Forward Current	3.4	
I <sub>FM</sub>	Diode Maximum Forward Current	22	
V <sub>GE</sub>	Gate-to-Emitter Voltage	±20	
V <sub>ISOL</sub>	Isolation Voltage, any terminal to case, 1 minute	2500	V <sub>RMS</sub>
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Maximum Power Dissipation, each IGBT	23	W
P <sub>D</sub> @ T <sub>C</sub> = 100°C	Maximum Power Dissipation, each IGBT	9.1	
T <sub>J</sub>	Operating Junction and	-40 to +150	°C
T <sub>STG</sub>	Storage Temperature Range		
	Soldering Temperature, for 10 sec.		
	300 (0.063 in. (1.6mm) from case)		
	Mounting torque, 6-32 or M3 screw.	5-7 lbf·in (0.55-0.8 N·m)	

### Thermal Resistance

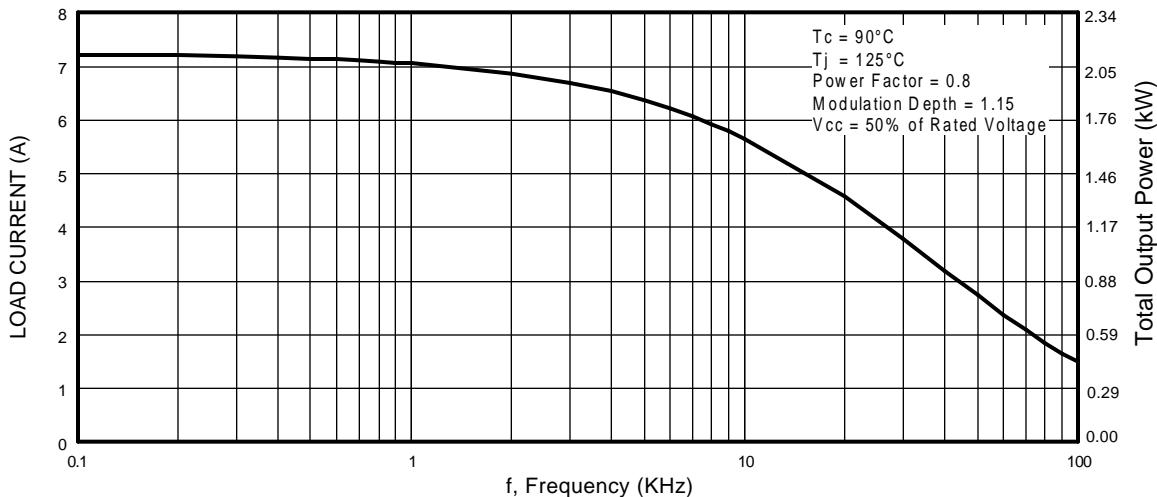
	Parameter	Typ.	Max.	Units
R <sub>θJC</sub> (IGBT)	Junction-to-Case, each IGBT, one IGBT in conduction	—	5.5	°C/W
R <sub>θJC</sub> (DIODE)	Junction-to-Case, each diode, one diode in conduction	—	9.0	
R <sub>θCS</sub> (MODULE)	Case-to-Sink, flat, greased surface	0.10	—	
Wt	Weight of module	20 (0.7)	—	g (oz)

**Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

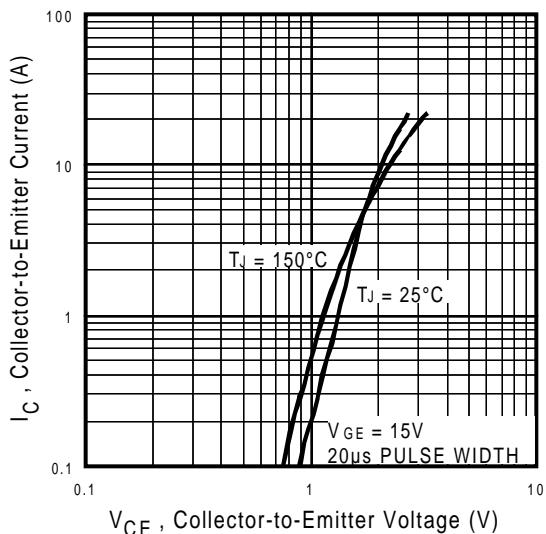
	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{CES}}$	Collector-to-Emitter Breakdown Voltage <sup>③</sup>	600	—	—	V	$V_{\text{GE}} = 0\text{V}$ , $I_C = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{CES}/\Delta T_J}$	Temperature Coeff. of Breakdown Voltage	—	0.63	—	V/ $^\circ\text{C}$	$V_{\text{GE}} = 0\text{V}$ , $I_C = 1.0\text{mA}$
$V_{\text{CE}(\text{on})}$	Collector-to-Emitter Saturation Voltage	—	1.70	2.2	V	$I_C = 3.9\text{A}$ $V_{\text{GE}} = 15\text{V}$
		—	1.95	—		$I_C = 7.2\text{A}$ See Fig. 2, 5
		—	1.70	—		$I_C = 3.9\text{A}$ , $T_J = 150^\circ\text{C}$
$V_{\text{GE}(\text{th})}$	Gate Threshold Voltage	3.0	—	6.0		$V_{\text{CE}} = V_{\text{GE}}$ , $I_C = 250\mu\text{A}$
$\Delta V_{\text{GE}(\text{th})/\Delta T_J}$	Temperature Coeff. of Threshold Voltage	—	-11	—	mV/ $^\circ\text{C}$	$V_{\text{CE}} = V_{\text{GE}}$ , $I_C = 250\mu\text{A}$
$g_{\text{fe}}$	Forward Transconductance <sup>④</sup>	1.4	4.3	—	S	$V_{\text{CE}} = 100\text{V}$ , $I_C = 6.5\text{A}$
$I_{\text{CES}}$	Zero Gate Voltage Collector Current	—	—	250	$\mu\text{A}$	$V_{\text{GE}} = 0\text{V}$ , $V_{\text{CE}} = 600\text{V}$
		—	—	2500		$V_{\text{GE}} = 0\text{V}$ , $V_{\text{CE}} = 600\text{V}$ , $T_J = 150^\circ\text{C}$
$V_{\text{FM}}$	Diode Forward Voltage Drop	—	1.4	1.7	V	$I_C = 8.0\text{A}$ See Fig. 13
		—	1.3	1.6		$I_C = 8.0\text{A}$ , $T_J = 150^\circ\text{C}$
$I_{\text{GES}}$	Gate-to-Emitter Leakage Current	—	—	$\pm 100$	nA	$V_{\text{GE}} = \pm 20\text{V}$

**Switching Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

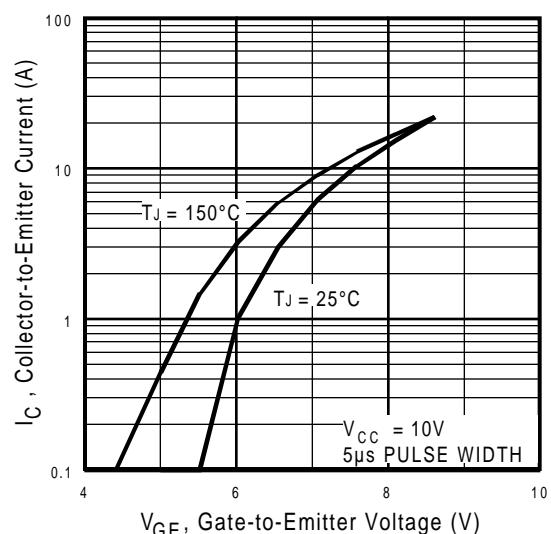
	Parameter	Min.	Typ.	Max.	Units	Conditions
$Q_g$	Total Gate Charge (turn-on)	—	31	47	nC	$I_C = 3.9\text{A}$
$Q_{\text{ge}}$	Gate - Emitter Charge (turn-on)	—	5.0	7.5		$V_{\text{CC}} = 400\text{V}$
$Q_{\text{gc}}$	Gate - Collector Charge (turn-on)	—	13	20		$V_{\text{GE}} = 15\text{V}$
$t_{\text{d(on)}}$	Turn-On Delay Time	—	45	—	ns	$T_J = 25^\circ\text{C}$
$t_r$	Rise Time	—	22	—		$I_C = 3.9\text{A}$ , $V_{\text{CC}} = 480\text{V}$
$t_{\text{d(off)}}$	Turn-Off Delay Time	—	100	160		$V_{\text{GE}} = 15\text{V}$ , $R_G = 50\Omega$
$t_f$	Fall Time	—	120	180		Energy losses include "tail" and diode reverse recovery. See Fig. 9, 10, 11, 18
$E_{\text{on}}$	Turn-On Switching Loss	—	0.13	—	mJ	
$E_{\text{off}}$	Turn-Off Switching Loss	—	0.07	—		
$E_{\text{ts}}$	Total Switching Loss	—	0.20	0.3		
$t_{\text{d(on)}}$	Turn-On Delay Time	—	42	—	ns	$T_J = 150^\circ\text{C}$ , See Fig. 9, 10, 11, 18
$t_r$	Rise Time	—	22	—		$I_C = 3.9\text{A}$ , $V_{\text{CC}} = 480\text{V}$
$t_{\text{d(off)}}$	Turn-Off Delay Time	—	120	—		$V_{\text{GE}} = 15\text{V}$ , $R_G = 50\Omega$
$t_f$	Fall Time	—	250	—		Energy losses include "tail" and diode reverse recovery.
$E_{\text{ts}}$	Total Switching Loss	—	0.35	—	mJ	
$C_{\text{ies}}$	Input Capacitance	—	530	—	pF	
$C_{\text{oes}}$	Output Capacitance	—	39	—	$V_{\text{CC}} = 30\text{V}$ See Fig. 7	
$C_{\text{res}}$	Reverse Transfer Capacitance	—	7.4	—	$f = 1.0\text{MHz}$	
$t_{\text{rr}}$	Diode Reverse Recovery Time	—	37	55	ns	$T_J = 25^\circ\text{C}$ See Fig.
		—	55	90		$T_J = 125^\circ\text{C}$ 14
$I_{\text{rr}}$	Diode Peak Reverse Recovery Charge	—	3.5	5.0	A	$T_J = 25^\circ\text{C}$ See Fig.
		—	4.5	8.0		$T_J = 125^\circ\text{C}$ 15
$Q_{\text{rr}}$	Diode Reverse Recovery Charge	—	65	138	nC	$T_J = 25^\circ\text{C}$ See Fig.
		—	124	360		$T_J = 125^\circ\text{C}$ 16
$dI_{(\text{rec})\text{M}/dt}$	Diode Peak Rate of Fall of Recovery During $t_b$	—	240	—	A/ $\mu\text{s}$	$T_J = 25^\circ\text{C}$ See Fig.
		—	210	—		$T_J = 125^\circ\text{C}$ 17



**Fig. 1 - Typical Load Current vs. Frequency**  
(Load Current =  $I_{RMS}$  of fundamental)



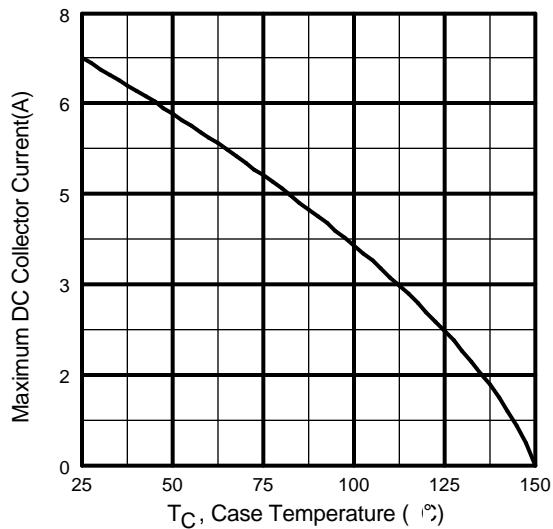
**Fig. 2 - Typical Output Characteristics**



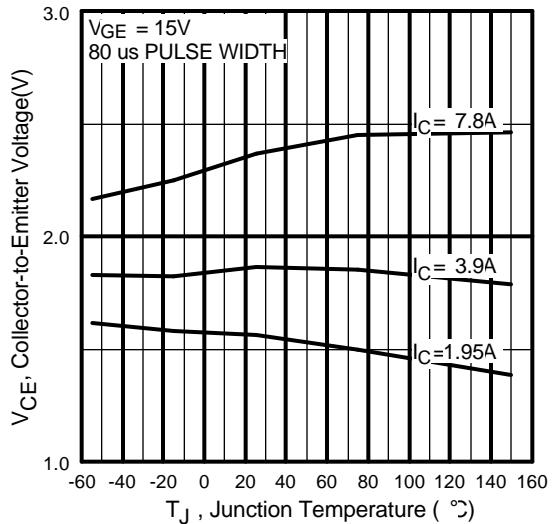
**Fig. 3 - Typical Transfer Characteristics**

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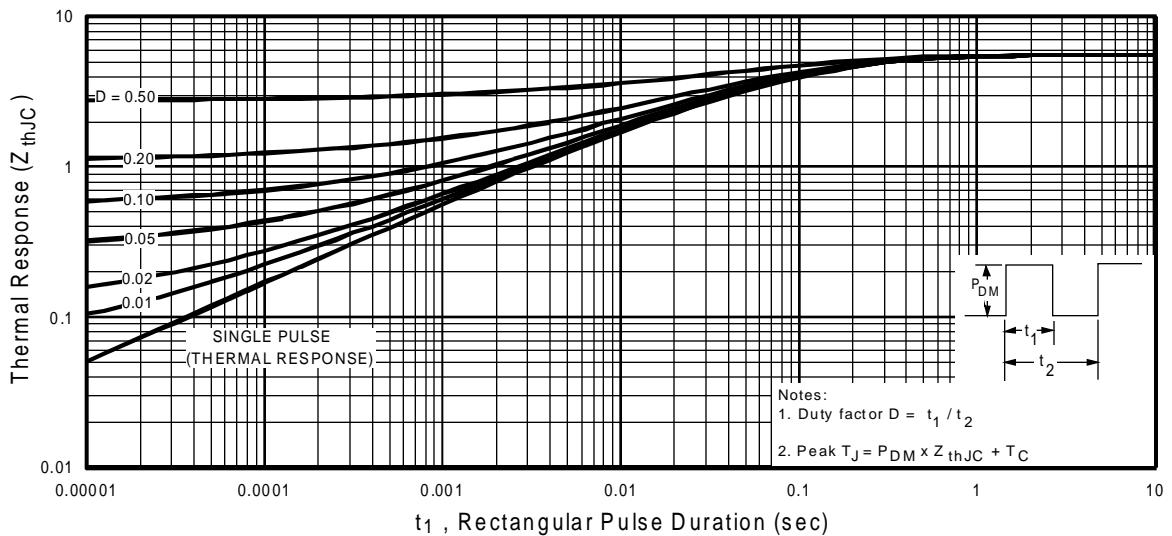
International  
Rectifier



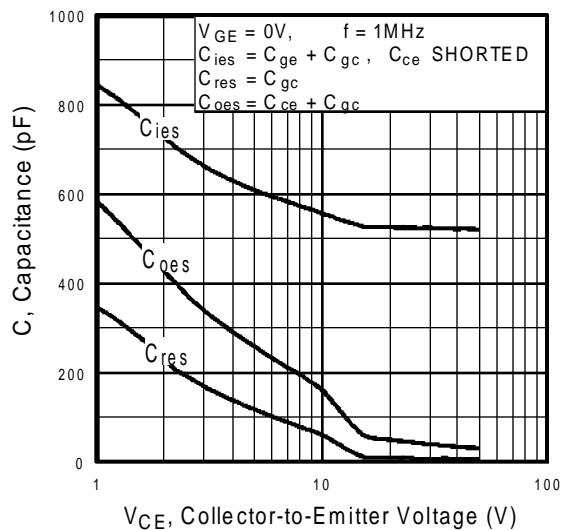
**Fig. 4 - Maximum Collector Current vs. Case Temperature**



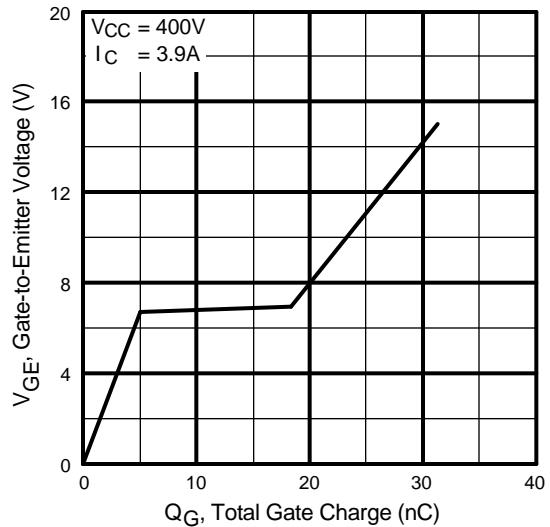
**Fig. 5 - Typical Collector-to-Emitter Voltage vs. Junction Temperature**



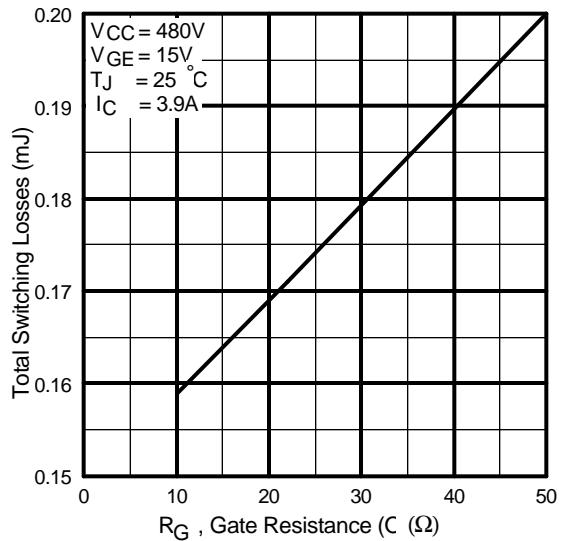
**Fig. 6 - Maximum Effective Transient Thermal Impedance, Junction-to-Case**



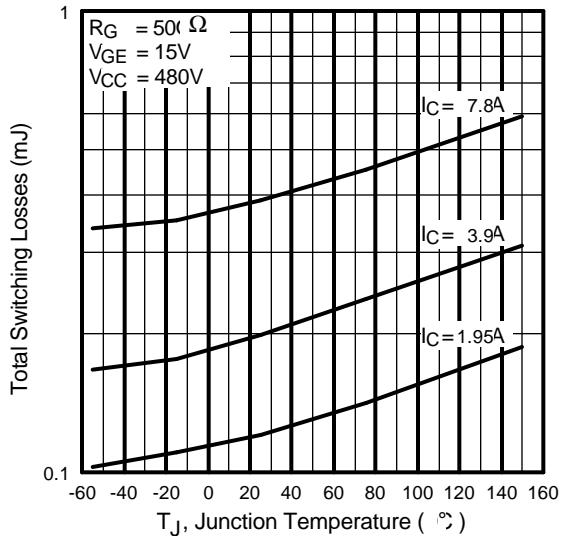
**Fig. 7 - Typical Capacitance vs. Collector-to-Emitter Voltage**



**Fig. 8 - Typical Gate Charge vs. Gate-to-Emitter Voltage**



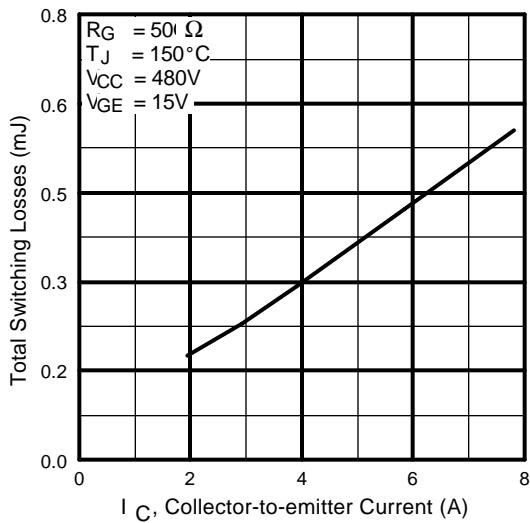
**Fig. 9 - Typical Switching Losses vs. Gate Resistance**



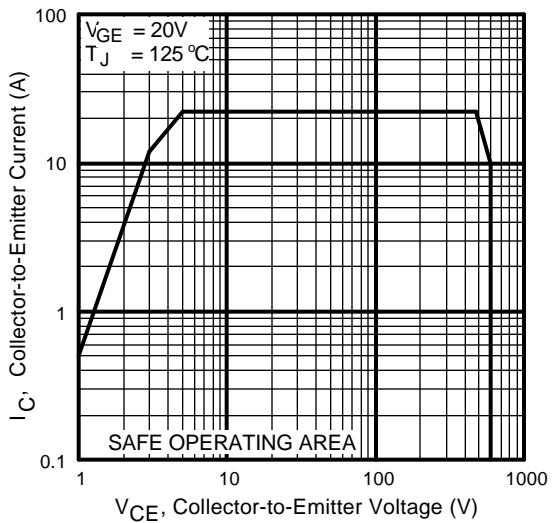
**Fig. 10 - Typical Switching Losses vs. Junction Temperature**

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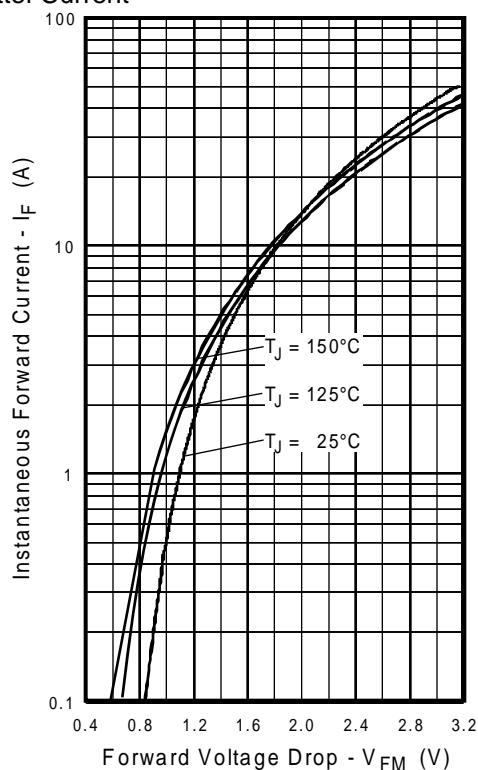
International  
**IR** Rectifier



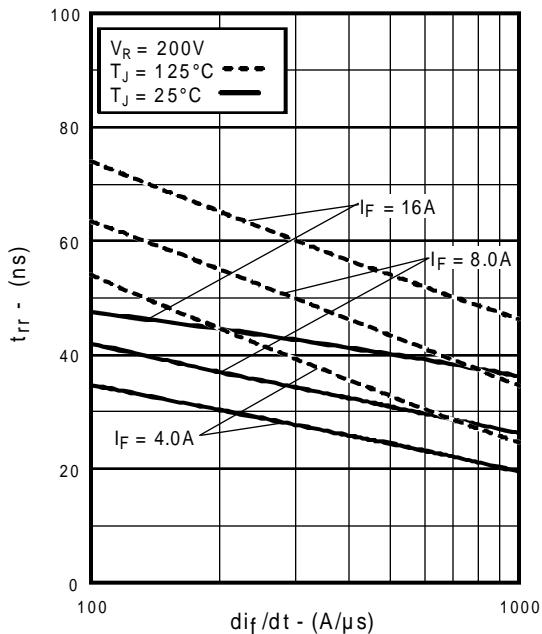
**Fig. 11** - Typical Switching Losses vs.  
Collector-to-Emitter Current



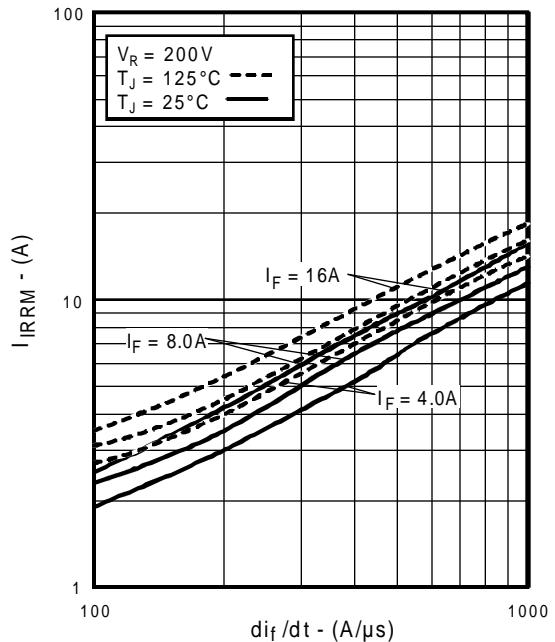
**Fig. 12** - Turn-Off SOA



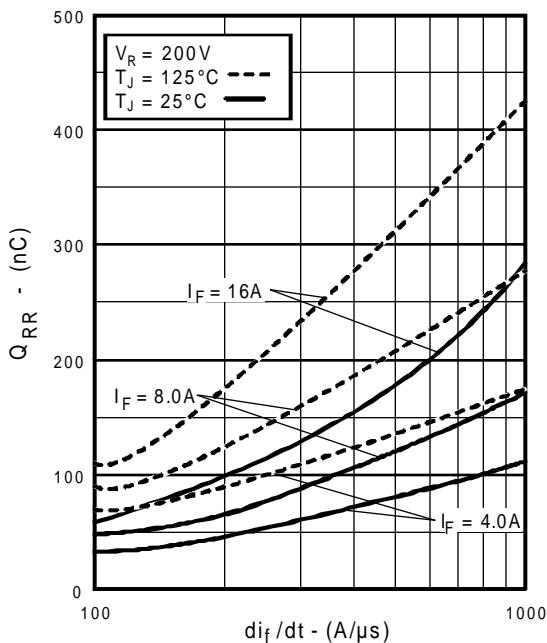
**Fig. 13** - Maximum Forward Voltage Drop vs. Instantaneous Forward Current



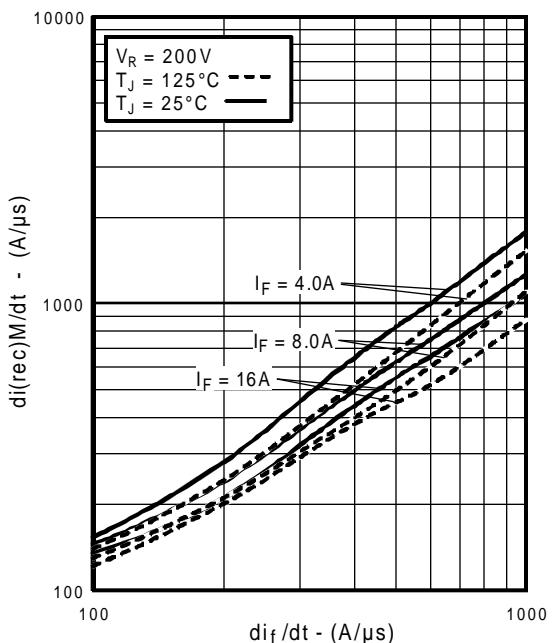
**Fig. 14 - Typical Reverse Recovery vs.  $di_f/dt$**



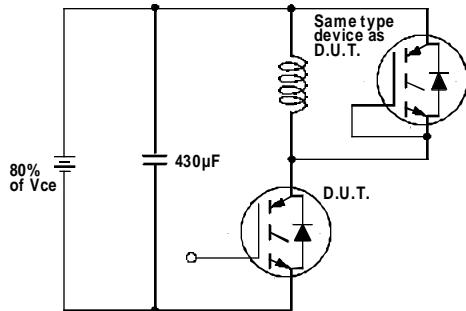
**Fig. 15 - Typical Recovery Current vs.  $di_f/dt$**



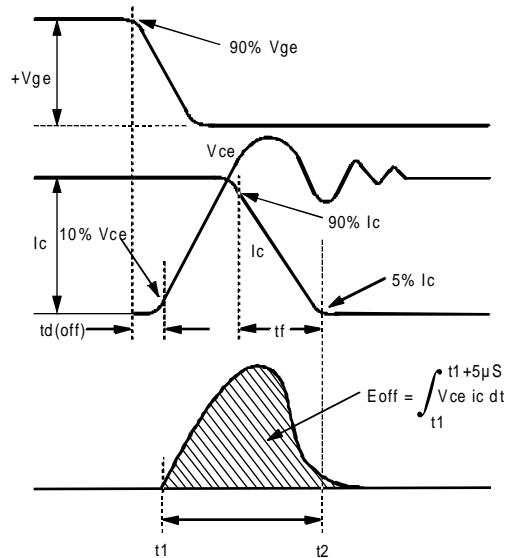
**Fig. 16 - Typical Stored Charge vs.  $di_f/dt$**



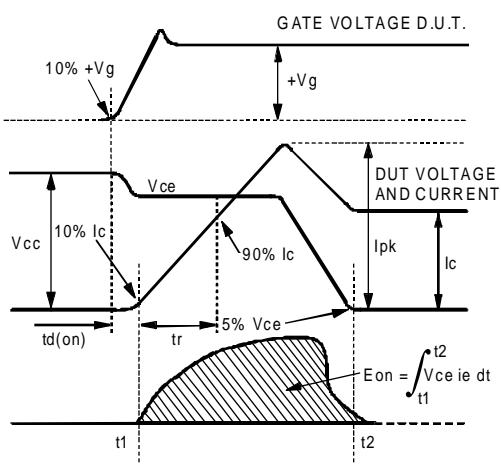
**Fig. 17 - Typical  $di_{(rec)}M/dt$  vs.  $di_f/dt$**



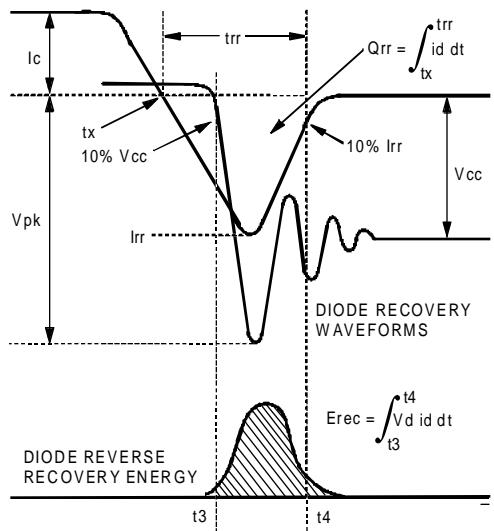
**Fig. 18a -** Test Circuit for Measurement of  $I_{LM}$ ,  $E_{on}$ ,  $E_{off(diode)}$ ,  $t_{rr}$ ,  $Q_{rr}$ ,  $I_{rr}$ ,  $t_d(on)$ ,  $t_r$ ,  $t_d(off)$ ,  $t_f$



**Fig. 18b -** Test Waveforms for Circuit of Fig. 18a, Defining  $E_{off}$ ,  $t_d(off)$ ,  $t_f$



**Fig. 18c -** Test Waveforms for Circuit of Fig. 18a, Defining  $E_{on}$ ,  $t_d(on)$ ,  $t_r$



**Fig. 18d -** Test Waveforms for Circuit of Fig. 18a, Defining  $E_{rec}$ ,  $t_{rr}$ ,  $Q_{rr}$ ,  $I_{rr}$

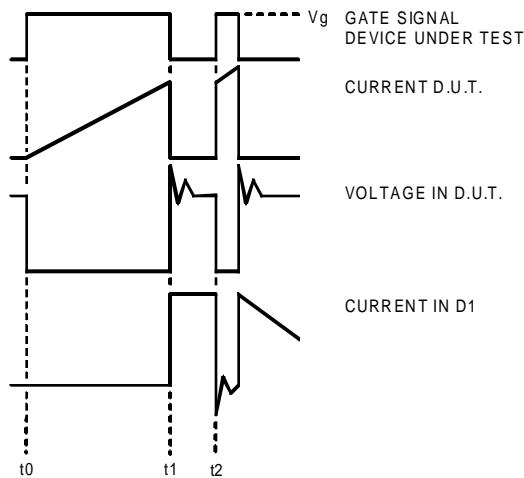


Figure 18e. Macro Waveforms for Figure 18a's Test Circuit

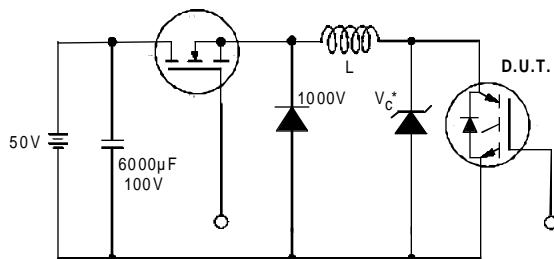


Figure 19. Clamped Inductive Load Test Circuit

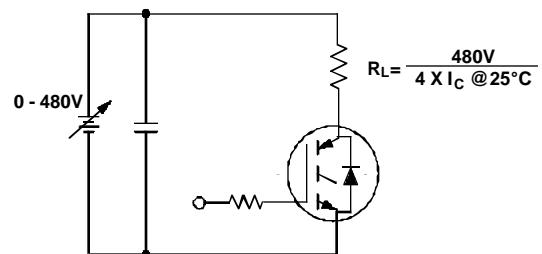
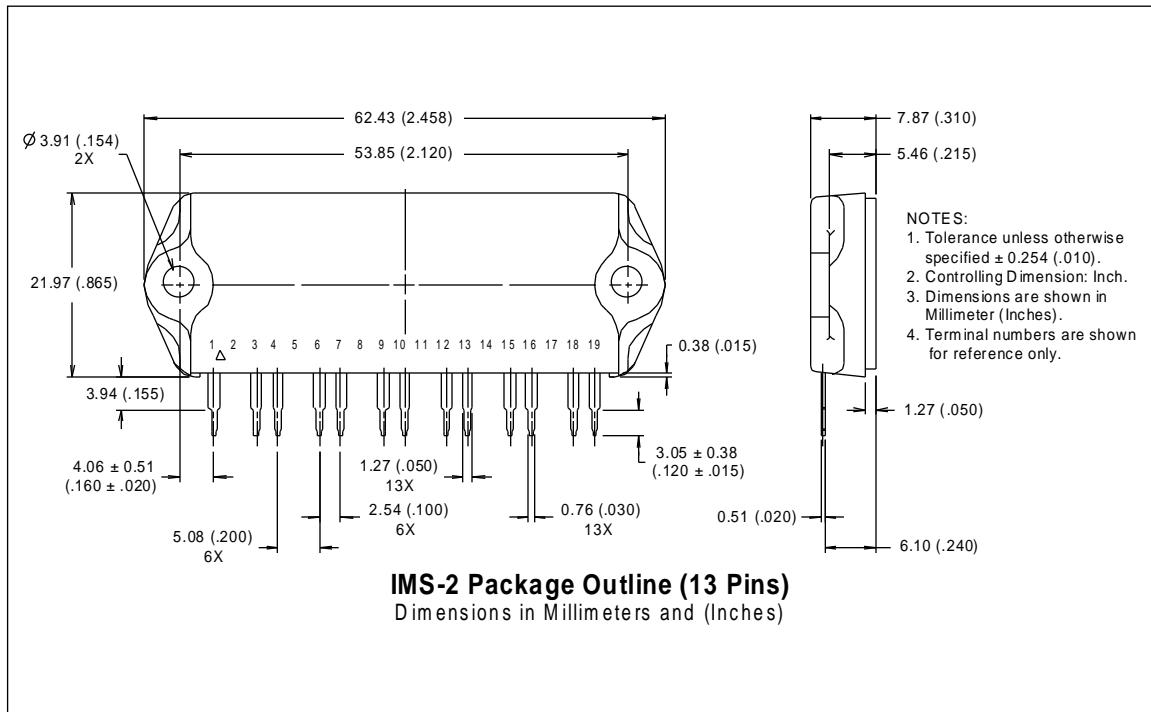


Figure 20. Pulsed Collector Current Test Circuit

## Notes:

- ① Repetitive rating:  $V_{GE}=20V$ ; pulse width limited by maximum junction temperature (figure 20)
- ②  $V_{CC}=80\% (V_{CES})$ ,  $V_{GE}=20V$ ,  $L=10\mu H$ ,  $R_G = 50\Omega$  (figure 19)
- ③ Pulse width  $\leq 80\mu s$ ; duty factor  $\leq 0.1\%$ .
- ④ Pulse width 5.0 $\mu s$ , single shot.

## Case Outline — IMS-2



International  
**IR** Rectifier

**WORLD HEADQUARTERS:** 233 Kansas St., El Segundo, California 90245, Tel: (310) 322 3331

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**IR CANADA:** 7321 Victoria Park Ave., Suite 201, Markham, Ontario L3R 2Z8, Tel: (905) 475 1897

**IR GERMANY:** Saalburgstrasse 157, 61350 Bad Homburg Tel: ++ 49 6172 96590

**IR ITALY:** Via Liguria 49, 10071 Borgaro, Torino Tel: ++ 39 11 451 0111

**IR FAR EAST:** K&H Bldg., 2F, 30-4 Nishi-Ikebukuro 3-Chome, Toshima-Ku, Tokyo Japan 171 Tel: 81 3 3983 0086

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